Se	Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/661,204	LAIL ET AL.	
Examiner	Art Unit	
Hae M. Hyeon	2839	

SEARCHED			
Class	Subclass	Date	Examiner
Search	Updated	7/06	hmh
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
385	100	1/06	hah
385	102	V	V

SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
Interference Text Search Done	11/05	hmh
		